

N-Channel Super Junction Power MOSFET $\, \mathrm{I\!V} \,$

General Description

The series of devices use advanced trench gate super junction technology and design to provide excellent R_{DS(ON)} with low gate charge. This super junction MOSFET fits the industry's AC-DC SMPS requirements for PFC, AC/DC power conversion, and industrial power applications.

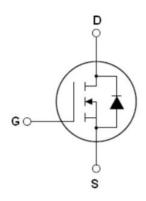
Features

- Optimized body diode reverse recovery performance
- ●Low on-resistance and low conduction losses
- Small package
- ●Ultra Low Gate Charge cause lower driving requirements
- ●100% Avalanche Tested
- ROHS compliant

Application

- Power factor correction (PFC)
- Switched mode power supplies(SMPS)
- Uninterruptible Power Supply (UPS)
- LLC Half-bridge

V _{DS min@Tjmax}	550	V
R _{DS(ON)TYP} .	1600	mΩ
I_D	1.9	Α
Qg	3.3	nC



Schematic diagram

Package Marking And Ordering Information

Device	Device Package	Marking
NCE50N1K8R	SOT-223-2L	NCE50N1K8R



SOT-223-2L

V1.0

Table 1. Absolute Maximum Ratings (T_c=25℃)

Parameter	Symbol	Value	Unit
Drain-Source Voltage (V _{GS=0} V)	V _{DS}	500	V
Gate-Source Voltage (VDS=0V) ,AC (f>1 Hz)	Vgs	±30	V
Gate-Source Voltage (VDS=0V) ,DC	Vgs	±20	V
Continuous Drain Current at Tc=25°C	I _{D (DC)}	1.9	A
Continuous Drain Current at Tc=100°C	I _{D (DC)}	1.33	A
Pulsed drain current (Note 1)	I _{DM (pluse)}	5.7	A
Maximum Power Dissipation(Tc=25℃)	P _D	4.7	W
Derate above 25°C		0.03	W/°C
Single pulse avalanche current (Note 2)	I _{AS}	1	A
Reverse diode dv/dt, $V_{DS} \leq 480 \text{ V,I}_{SD} < I_{D}$	dv/dt	15	V/ns
Drain Source voltage slope,V _{DS} ≤480 V	dv/dt	50	V/ns
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55+175	°C

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Table 2. Thermal Characteristic

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Maximum)	R _{thJC}	31.91	°C /W
Thermal Resistance, Junction-to-Ambient (Maximum)	R _{thJA}	62	°C /W

 Table 3. Electrical Characteristics (TA=25℃unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
On/off states				•	. '	
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250uA	500			V
Zero Gate Voltage Drain Current(Tc=25℃)	I _{DSS}	V _{DS} =500V,V _{GS} =0V			1	μA
Zero Gate Voltage Drain Current(Tc=125°C)	I _{DSS}	V _{DS} =500V,V _{GS} =0V			50	μA
Gate-Body Leakage Current	I _{GSS}	$V_{GS}=\pm20V, V_{DS}=0V$			±200	nA
Gate Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS},I_{D}=250uA$	2.5	3.2	4	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =1A		1600	1800	mΩ
Dynamic Characteristics						
Gate Resistance	Rg	F=1MHZ, D-S short		17.5		Ω
Input Capacitance	C _{lss}	\/ _F0\/\/ _0\/		110		pF
Output Capacitance	Coss	V_{DS} =50V, V_{GS} =0V,		11		pF
Reverse Transfer Capacitance	C _{rss}	F=1MHz		1.7		pF
Total Gate Charge	Qg			3.3		nC
Gate-Source Charge	Q _{gs}	V_{DS} =400 V , I_{D} =1 A ,		0.34		nC
Gate-Drain Charge	Q_{gd}	V _{GS} =10V		0.71		nC
Gate plateau voltage	Vgp			5.2		V
Switching times						
Turn-on Delay Time	t _{d(on)}			6.4		nS
Turn-on Rise Time	tr	V_{DD} =380 V , I_D =1 A ,		5.5		nS
Turn-Off Delay Time	t _{d(off)}	R_{G} =4 Ω , V_{GS} =10 V		22		nS
Turn-Off Fall Time	t _f			28		nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	I _{SD}	T -05°0			1.9	Α
Pulsed-Source-drain current(Body Diode)	I _{SDM}	T _C =25°C			5.7	Α
Forward on voltage	V _{SD}	Tj=25°C,I _{SD} =1.9A,V _{GS} =0V		0.9	1.1	V
Reverse Recovery Time	t _{rr}	T: 05°0 L 4A		125		nS
Reverse Recovery Charge	Q _{rr}	Tj=25°C,I _F =1A,		0.41		uC
Peak reverse recovery current	I _{rrm}	di/dt=100A/μs		6.5		Α

Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature

2. Tj=25 $^{\circ}\text{C}$,VDD=50V,VG=10V, RG=25 Ω



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (curves)

Figure 1. Safe operating area

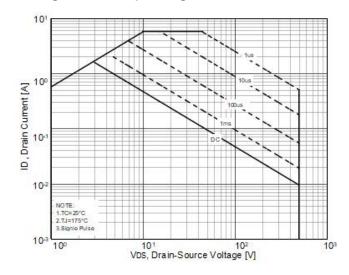


Figure 2. Source-Drain Diode Forward Voltage

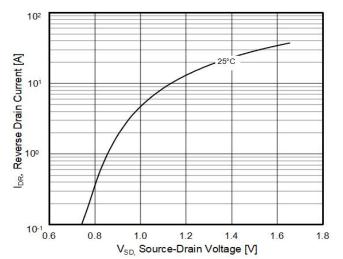


Figure 3. Output characteristics

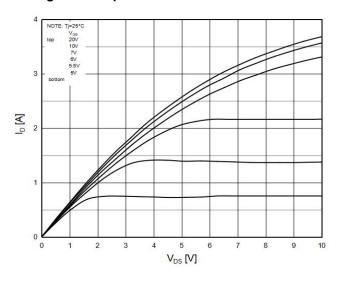


Figure 4. Transfer characteristics

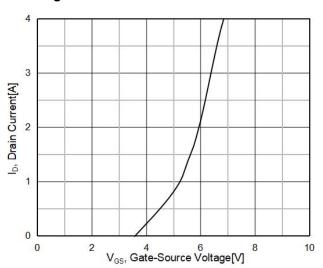


Figure 5. Static drain-source on resistance

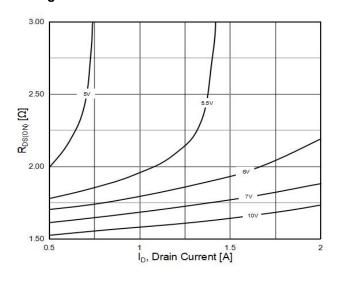
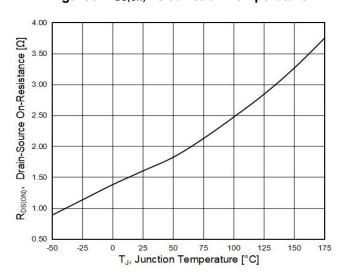


Figure 6. RDS(ON) vs Junction Temperature



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Figure 7. BV_{DSS} vs Junction Temperature

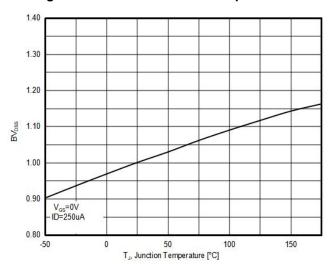


Figure 8. Maximum $I_{\mbox{\scriptsize D}}$ vs Junction Temperature

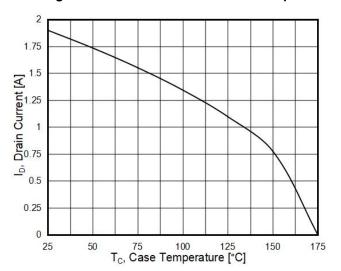


Figure 9. Gate charge waveforms

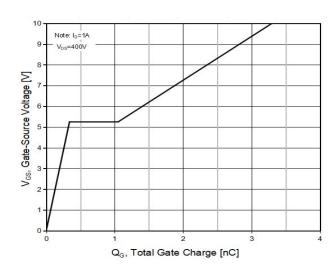
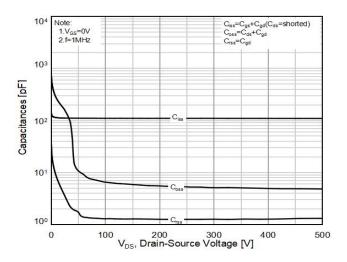


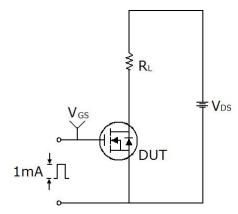
Figure 10. Capacitance

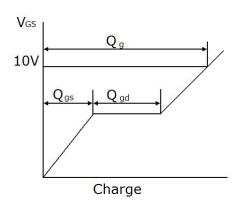




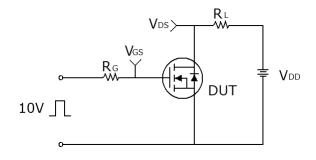
Test circuit

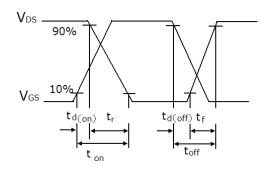
1) Gate charge test circuit & Waveform



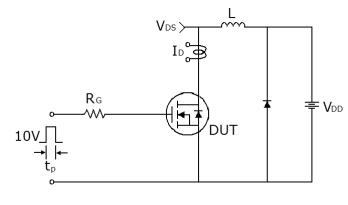


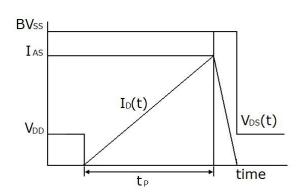
2) Switch Time Test Circuit:





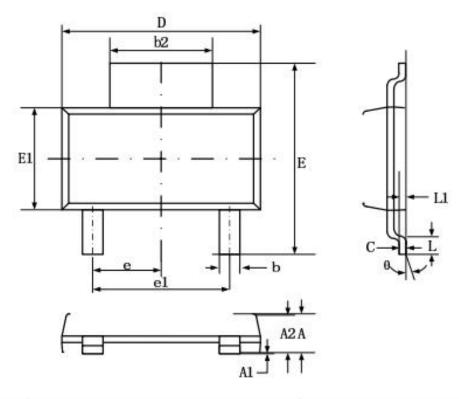
3) Unclamped Inductive Switching Test Circuit & Waveforms







SOT-223-2L-B Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
Α	0	1.80		0.071
A1	0.02	0.10	0.001	0.004
A2	1.50	1.70	0.059	0.067
b	0.66	0.84	0.026	0.033
b2	2.90	3.10	0.114	0.122
С	0.23	0.35	0.009	0.014
D	6.30	6.70	0.248	0.264
Е	6.70	7.30	0.264	0.287
E1	3.30	3.70	0.130	0.146
е	2.30 BSC.		0.091	BSC.
e1	4.60	60 BSC. 0.182 BSC.		BSC.
L	0.81	3 -3- 3	0.032	(



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